Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/904,042	HAN, K. MICHAEL
Examiner	Art Unit

Edward Wojciechowicz

2815

SEARCHED						
Class	Subclass	Date	Examiner			
<i>ბ</i> \$7	314, 333 353	3-15-05	Edi			
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INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
314,3 3 3 353	3-15-05	EH			
	314,333	314,333			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
EAST 257/314,333,353	3-15-05	Ch			
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